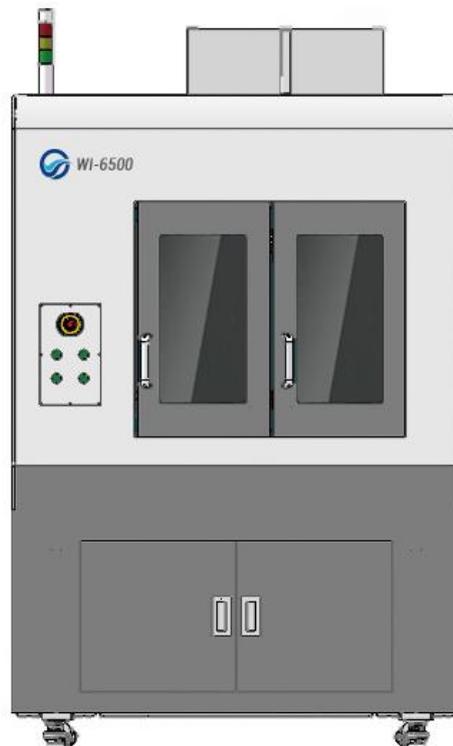
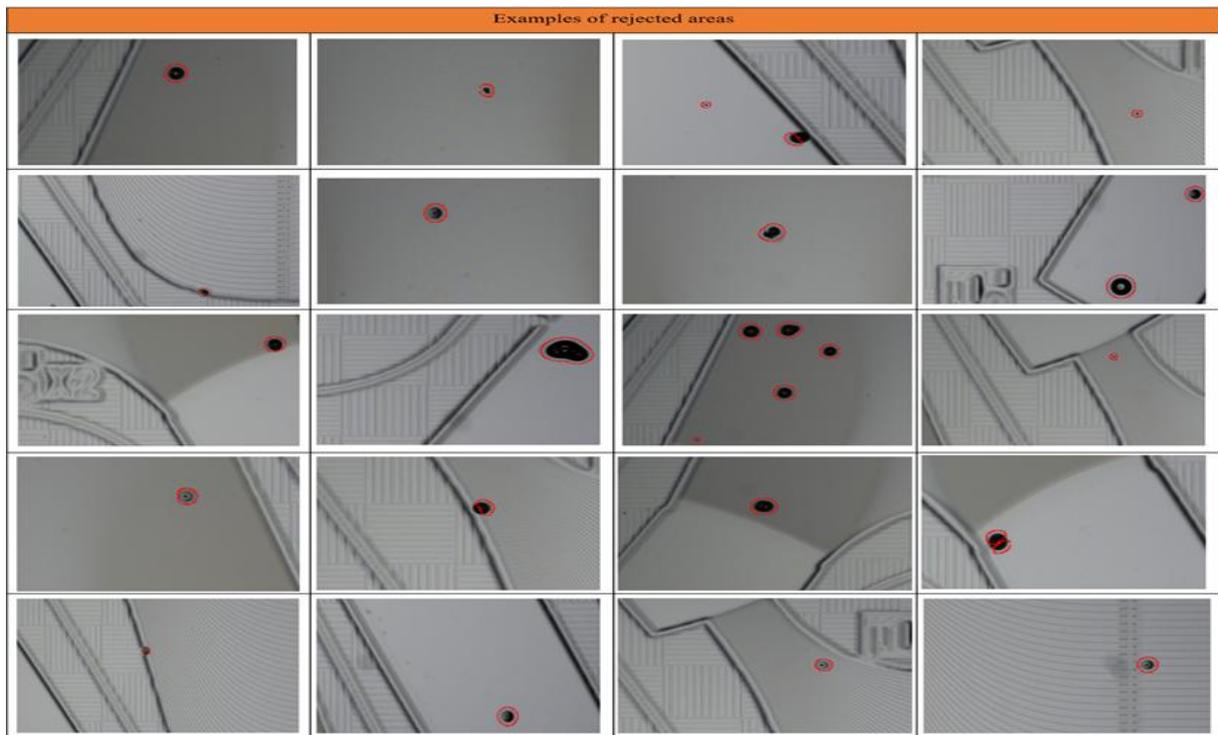


WI-6500 Wafer Defect Inspection System



1. Description

WI-6500 supports 25 wafer automatic-defect inspection systems. 25 6-inch wafers are carried into the system inspection wafer cassette by the shipping wafer cassette, the equipment closes the hatch. The vision system scans the number and position of the wafers in the cassette, and then the robot arm moves the wafer to the pre-aligner to align the wafers. The wafer then will be transferred to the front defect inspection module tray for rapid defect detection and extraction of defective images. After the inspection is completed, the system generates a defect map and simultaneously stores the result in the production line system database for operators and engineers to analyze the situation of defect of products.



2. Specifications

Defect detection system		
Detection type	Brightfield and darkfield	OK
Imaging type	Color / black and white	OK
Detection magnification	1.25X, 2.5X, 5X, 10X, 20X	OK
Defect review	Manual / automatic defect review	OK
Measurement results upload to production line system	Interface test results with production line systems	OK
Automatic classification of defects	Quickly and accurately classify and summarize defect areas, sizes, etc.	OK
Measurement time	Each wafer \leq 30min (6inch)	OK
Defect capture rate	Typical: 99% @3 pixels size defects	OK
Defect loss rate	Typical: 1%	OK
Recheck rate	Typical: 1%	OK
Anti-vibration platform	The device needs to be equipped with a vibration isolation platform to prevent detection results from being disturbed by external vibrations	OK

Silicon wafer stage		
Compatible wafer size	6 inch / 8 inch wafer	OK
Autofocus	The lens is equipped with a Z-axis motor for automatic focusing	OK
XY and rotary stage	XY-direction tage is required for inspection, and rotation stage is required for calibration	OK
Automatic loading		
Equipment loading	One wafer cassette at a time, at least 25 wafers one cassette	OK
Pre-calibration	Automatic pre-calibration before loading into wafer chuck	OK
Submodule	Automatic loading can be used as a sub-module, optional according to user needs	OK
Software requirements		
Friendly user interface	Modular design, simple operation. Convenient to add new types of wafer inspection	OK
Interface language	Support Chinese and English. Convenient for local and foreign users	OK
Editable parameters	Customers edit corresponding detection parameters as needed	OK
Review function	Provide online or offline defect review	OK
Terms of service		
Service guarantee	7 days / 24 hours / 6 months of full real-time service support, and ensure all the relevant personnel are trained to use the local system and software during the period. Otherwise it will extend the service time. If the equipment is used in Wuhan in China, the service reply is guaranteed within 1 hour, and it will be on site within 4 hours	OK
Installation	In order to ensure the normal operation of the equipment, the seller needs to send experienced technicians to the buyer's contract equipment site for installation, commissioning and technical guidance	OK
Warranty	After acceptance, the warranty period is 1 year	OK
Other to be added		